Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/699,117	PARK ET AL.
Examiner	Art Unit
Tao H. Voon	1714

SEARCHED				
Class	Subclass	Date	Examiner	
523	116	1-13-06	W	
	120			
433	228.1	5-22-06	4	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
523	116	5-22-06	y		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	1-13-06	ny		
Inventor Seard	1-21-06	y		
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